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N-channel 800 V, 0.37 Ω typ., 12 A MDmesh™ K5 Power MOSFET in a TO-220FP ultra narrow leads package

Datasheet - production data

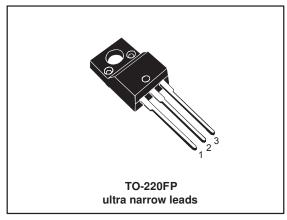
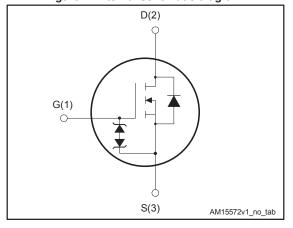


Figure 1: Internal schematic diagram



Features

| Order code | V _{DS} | R _{DS(on)} max | ID | Ртот |
|-------------|-----------------|-------------------------|------|------|
| STFU13N80K5 | 800 V | 0.45 Ω | 12 A | 35 W |

- Industry's lowest R_{DS(on)} x area
- Industry's best FoM (figure of merit)
- Ultra-low gate charge
- 100% avalanche tested
- Zener-protected

Applications

• Switching applications

Description

This very high voltage N-channel Power MOSFET is designed using MDmesh™ K5 technology based on an innovative proprietary vertical structure. The result is a dramatic reduction in on-resistance and ultra-low gate charge for applications requiring superior power density and high efficiency.

Table 1: Device summary

| Order code | Marking | Package | Packing |
|-------------|---------|-----------------------------|---------|
| STFU13N80K5 | 13N80K5 | TO-220FP ultra narrow leads | Tube |

Contents STFU13N80K5

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STFU13N80K5 Electrical ratings

1 Electrical ratings

Table 2: Absolute maximum ratings

| Symbol | Parameter | Value | Unit |
|--------------------------------|---|------------|------|
| V _G s | Gate source voltage | ±30 | V |
| I _D ⁽¹⁾ | Drain current (continuous) at T _C = 25 °C | 12 | Α |
| I _D ⁽¹⁾ | Drain current (continuous) at T _C = 100 °C | 7.6 | Α |
| I _{DM} ⁽²⁾ | Drain current (pulsed) | 48 | Α |
| Ртот | Total dissipation at T _C = 25 °C 35 | | W |
| I _{AS} | Max current during repetitive or single pulse avalanche (pulse width limited by T _{jmax}) | | Α |
| Eas | Single pulse avalanche energy (starting T_J = 25 °C, I_D = I_{AS} , V_{DD} = 50 V) | | mJ |
| V _{ISO} | Insulation withstand voltage (RMS) from all three leads to external heat sink (t = 1 s; T _C = 25 °C) | | ٧ |
| dv/dt (3) | Peak diode recovery voltage slope | 4.5 | V/ns |
| dv/dt (4) | MOSFET dv/dt ruggedness 50 | | V/ns |
| T _{stg} | Storage temperature range | EE to 150 | °C |
| Tj | Operating junction temperature range | -55 to 150 | |

Notes:

Table 3: Thermal data

| Symbol | Parameter Value | | Unit |
|-----------------------|--|------|------|
| R _{thj-case} | Thermal resistance junction-case | 3.57 | °C/W |
| R _{thj-amb} | thi-amb Thermal resistance junction-ambient 62.5 | | C/VV |

⁽¹⁾Limited by package.

⁽²⁾Pulse width limited by safe operating area.

 $^{^{(3)}}I_{SD} \le$ 12 A, di/dt \le 100 A/ μ s, $V_{DS(peak)} \le V_{(BR)DSS}$.

 $^{^{(4)}}V_{SD} \le 640 \text{ V}.$

2 Electrical characteristics

(T_C = 25 °C unless otherwise specified)

Table 4: On /off states

| Symbol | Parameter | Test conditions | Min. | Тур. | Max. | Unit |
|----------------------|-----------------------------------|---|------|------|------|------|
| V _{(BR)DSS} | Drain-source breakdown voltage | V _{GS} = 0 V, I _D = 1 mA | 800 | | | ٧ |
| | Zero gate voltage | V _{GS} = 0 V, V _{DS} = 800 V | | | 1 | μΑ |
| IDSS | drain current | $V_{GS} = 0 \text{ V}, V_{DS} = 800 \text{ V},$ $T_{C} = 125 ^{\circ}\text{C}^{(1)}$ | | | 50 | μΑ |
| I _{GSS} | Gate-body leakage current | V _{DS} = 0 V, V _{GS} = ±20 V | | | ±10 | μA |
| V _{GS(th)} | Gate threshold voltage | $V_{DS} = V_{GS}, I_{D} = 100 \mu A$ | 3 | 4 | 5 | V |
| R _{DS(on)} | Static drain-source on-resistance | V _{GS} = 10 V, I _D = 6 A | | 0.37 | 0.45 | Ω |

Notes:

Table 5: Dynamic

| Symbol | Parameter | Test conditions | Min. | Тур. | Max. | Unit |
|-----------------------------------|---------------------------------------|--|------|------|------|------|
| Ciss | Input capacitance | | - | 870 | - | pF |
| Coss | Output capacitance | V _{DS} = 100 V, f = 1 MHz, | - | 50 | ı | pF |
| Crss | Reverse transfer capacitance | V _{es} = 0 V | - | 2 | ı | pF |
| C _{o(tr)} ⁽¹⁾ | Equivalent output capacitance | V = 0 V V = 0 to 640 V | - | 110 | ı | pF |
| Co(er) ⁽²⁾ | Equivalent capacitance energy related | V _{GS} = 0 V, V _{DS} = 0 to 640 V | | 43 | | pF |
| R _G | Intrinsic gate resistance | f = 1 MHz, I _D = 0 A | - | 5 | - | Ω |
| Qg | Total gate charge | V _{DD} = 640 V, I _D = 12 A, | - | 29 | 1 | nC |
| Qgs | Gate-source charge | V _{GS} = 0 to 10 V (see Figure 16: "Test circuit for | - | 7 | - | nC |
| Q _{gd} | Gate-drain charge | gate charge behavior") | - | 18 | - | nC |

Notes

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 $[\]ensuremath{^{(1)}}\mbox{Defined}$ by design, not subject to production test.

 $^{^{(1)}}$ Time related is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS} .

 $^{^{(2)}}$ Energy related is defined as a constant equivalent capacitance giving the same stored energy as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS} .

Table 6: Switching times

| Tuble 0. Owitoning times | | | | | | |
|--------------------------|---------------------|---|------|------|------|------|
| Symbol | Parameter | Test conditions | Min. | Тур. | Max. | Unit |
| t _{d(on)} | Turn-on delay time | V _{DD} = 400 V, I _D = 6 A, | - | 16 | - | ns |
| tr | Rise time | R _G = 4.7 Ω , V _{GS} = 10 V (see Figure 15: "Test circuit for | - | 16 | 1 | ns |
| t _{d(off)} | Turn-off delay time | resistive load switching times" | 1 | 42 | 1 | ns |
| t _f | Fall time | and Figure 20: "Switching time waveform") | - | 16 | - | ns |

Table 7: Source drain diode

| Symbol | Parameter | Test conditions | Min. | Тур. | Max. | Unit |
|--------------------------------|-------------------------------|---|------|------|------|------|
| I _{SD} | Source-drain current | | - | | 14 | Α |
| I _{SDM} | Source-drain current (pulsed) | | 1 | | 56 | А |
| V _{SD} ⁽¹⁾ | Forward on voltage | I _{SD} = 12 A, V _{GS} = 0 V | 1 | | 1.5 | V |
| trr | Reverse recovery time | I _{SD} = 12 A, di/dt = 100 A/μs, | - | 406 | | ns |
| Qrr | Reverse recovery charge | V _{DD} = 60 V (see Figure 17: "Test circuit for | - | 5.7 | | μC |
| I _{RRM} | Reverse recovery current | inductive load switching and diode recovery times") | - | 28 | | Α |
| t _{rr} | Reverse recovery time | I _{SD} = 12 A, di/dt = 100 A/μs, | - | 600 | | ns |
| Qrr | Reverse recovery charge | V_{DD} = 60 V, T_j = 150 °C (see <i>Figure 17: "Test circuit for</i> | - | 7.9 | | μC |
| I _{RRM} | Reverse recovery current | inductive load switching and diode recovery times") | - | 26 | | Α |

Notes:

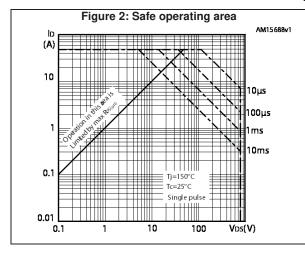
Table 8: Gate-source Zener diode

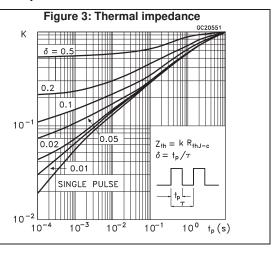
| Symbol | Parameter | Test conditions | Min. | Тур. | Max. | Unit |
|----------------------|-------------------------------|---|------|------|------|------|
| V _{(BR)GSO} | Gate-source breakdown voltage | $I_{GS} = \pm 1 \text{mA}, I_{D} = 0 \text{ A}$ | 30 | - | - | V |

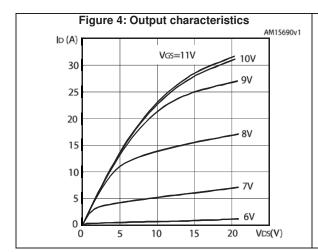
The built-in back-to-back Zener diodes are specifically designed to enhance the ESD performance of the device. The Zener voltage facilitates efficient and cost-effective device integrity protection, thus eliminating the need for additional external componentry.

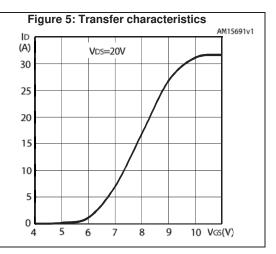
 $^{^{(1)}}$ Pulsed: pulse duration = 300 μ s, duty cycle 1.5%.

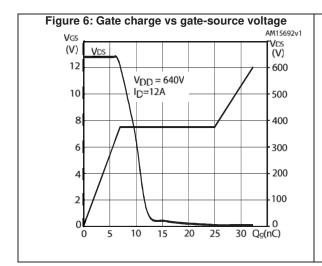
2.1 Electrical characteristics (curves)

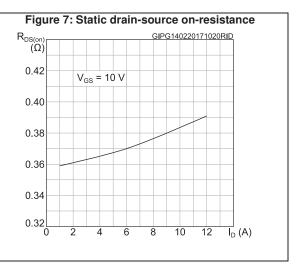












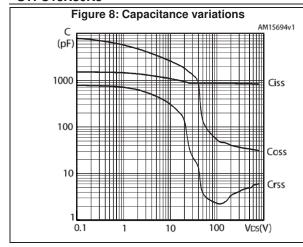


Figure 9: Source-drain diode forward characteristics (V) TJ=-50°C 0.9 0.8 TJ=25°C 0.7 TJ=150°C 0.6 0.5 2 4 6 8 10 ISD(A)

Figure 10: Normalized gate threshold voltage vs temperature

VGS(th)
(norm)
1.2

1

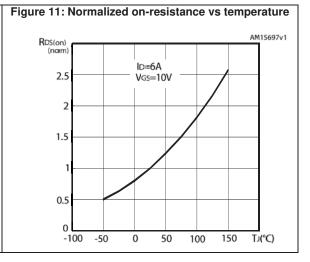
0.8

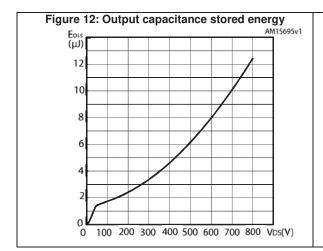
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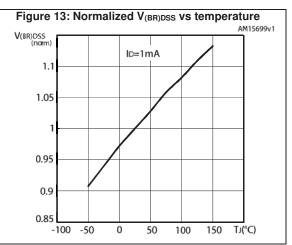
0.4

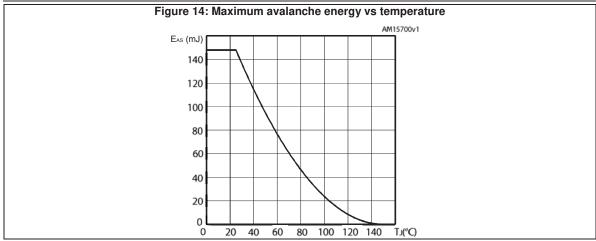
0.2

-100 -50 0 50 100 150 TJ(°C)









STFU13N80K5 Test circuit

3 **Test circuit**

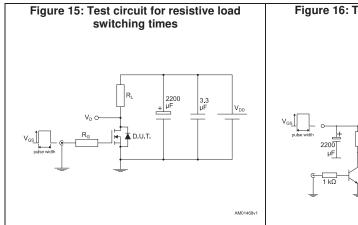
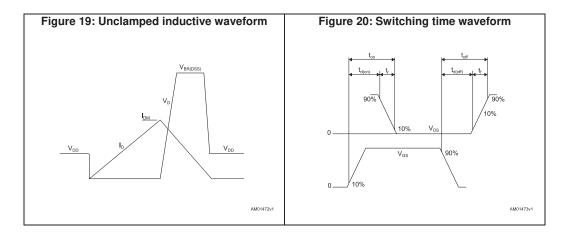


Figure 16: Test circuit for gate charge behavior 1 kΩ ⊥ 100 nF I_G= CONST 2.7 kΩ 47 kΩ

circuit

★ D.U.T.

Figure 17: Test circuit for inductive load Figure 18: Unclamped inductive load test switching and diode recovery times



AM01471v1

4 **Package information**

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK® is an ST trademark.

4.1 TO-220FP ultra narrow leads package information

Figure 21: TO-220FP ultra narrow leads package outline Н G1 Ε 8576148_1

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Table 9: TO-220FP ultra narrow leads mechanical data

| Dim | | mm | |
|------|-------|------|-------|
| Dim. | Min. | Тур. | Max. |
| А | 4.40 | | 4.60 |
| В | 2.50 | | 2.70 |
| D | 2.50 | | 2.75 |
| E | 0.45 | | 0.60 |
| F | 0.65 | | 0.75 |
| F1 | - | | 0.90 |
| G | 4.95 | | 5.20 |
| G1 | 2.40 | 2.54 | 2.70 |
| Н | 10.00 | | 10.40 |
| L2 | 15.10 | | 15.90 |
| L3 | 28.50 | | 30.50 |
| L4 | 10.20 | | 11.00 |
| L5 | 2.50 | | 3.10 |
| L6 | 15.60 | | 16.40 |
| L7 | 9.00 | | 9.30 |
| L8 | 3.20 | | 3.60 |
| L9 | - | | 1.30 |
| Dia. | 3.00 | | 3.20 |

Revision history STFU13N80K5

5 Revision history

Table 10: Document revision history

| Date | Revision | Changes |
|-------------|----------|--|
| 08-Oct-2015 | 1 | Initial release |
| 14-Jul-2017 | 2 | Modified Figure 7: "Static drain-source on-resistance". Minor text changes. |

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